

**Search Notes**

Application/Control No.

10/501,917

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

KATSUNUMA, TAKAYUKI

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	711	4/21/2006	BT
438	713	4/21/2006	BT
438	728	4/21/2006	BT
438	743	4/21/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventor's name using USPAT, USPGPUB, JPO, EPO, DERWENT database	4/21/2006	BT